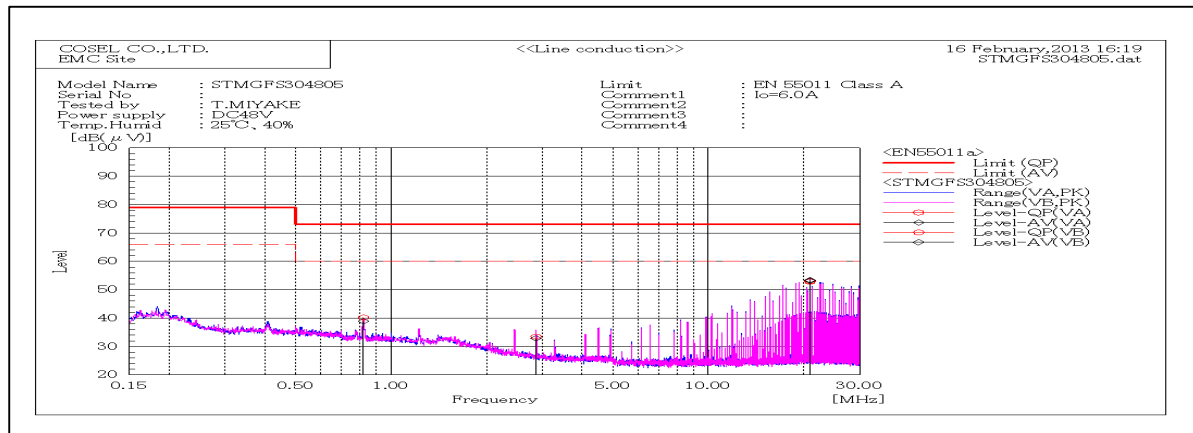
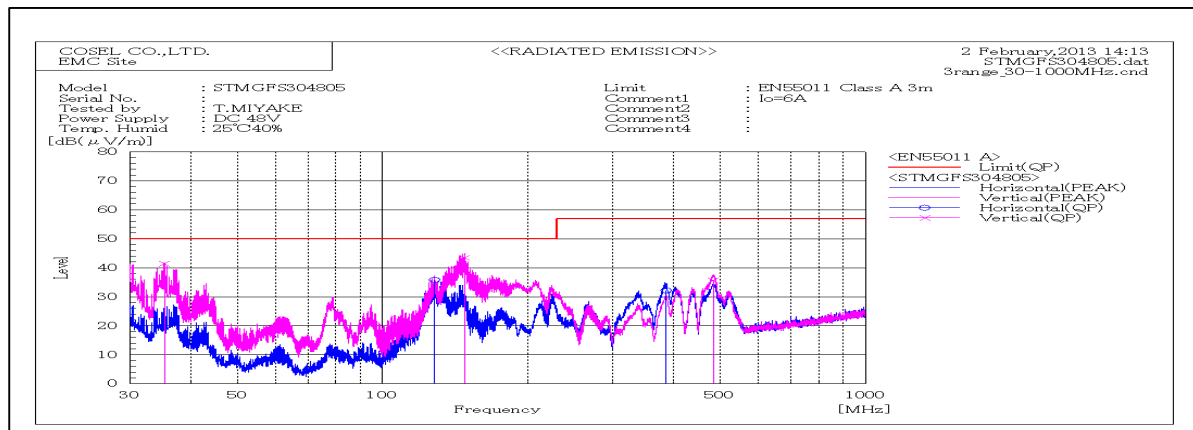


DATA SHEET		Date	18-Feb-13
Model	STMGFS304805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



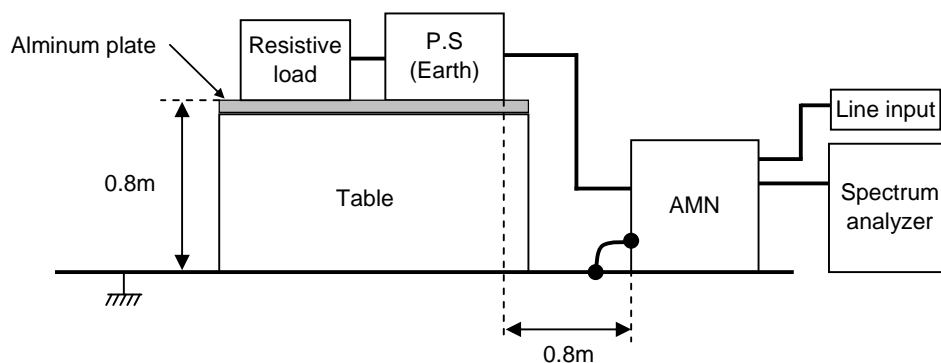
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.81947		VB	20.1	18.8	20.1	40.2	38.9	73	60	32.8	21.1	Pass	
2.8662		VA	13.2	12.6	20.3	33.5	32.9	73	60	39.5	27.1	Pass	
20.90035		VA	31.9	32.2	21.2	53.1	53.4	73	60	19.9	6.6	Pass	
20.90025		VB	31.6	32	21.2	52.8	53.2	73	60	20.2	6.8	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV					
35.328	V	Stable	56.4		-15	41.4		8.6	Pass	102	179	
128.154	H	Stable	55.4		-19.6	35.8		14.2	Pass	142	243	
147.858	V	Stable	61.3		-17.8	43.5		6.5	Pass	112	274	
386.478	H	Stable	44.8		-12.6	32.2		24.8	Pass	103	74	
483.859	V	Stable	48.1		-12.5	35.6		21.4	Pass	106	319	

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

